CSD17570Q5B 30V N 沟道 NexFET™功率金属氧化物半导体场效应晶体管 (MOSFET)

1 特性

- 超低电阻
- 低热阻
- 雪崩级
- 无铅引脚镀层
- 符合 RoHS 标准
- 无卤素
- 小外形尺寸无引线 (SON) 5mm x 6mm 塑料封装

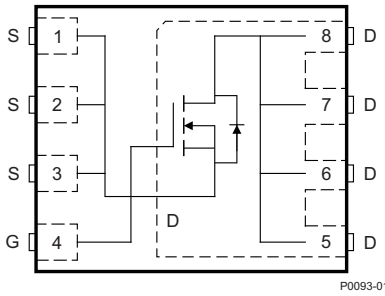
2 应用

- ORing 和热插拔 应用

3 说明

这款 30V，0.56mΩ，SON 5mm × 6mmNexFET™功率 MOSFET 旨在最大限度地减小 ORing 和热拔插应用的 电阻， 不可用于开关 应用。

顶部图标



P0093-01

产品概要

T_A = 25°C		典型值		单位
V_{DS}	漏源电压	30		V
Q_g	栅极电荷总量 (4.5V)	93		nC
Q_{gd}	栅极电荷（栅极到漏极）	34		nC
$R_{DS(on)}$	漏源导通电阻	V_{GS} = 4.5V	0.74	mΩ
		V_{GS} = 10V	0.56	mΩ
$V_{GS(th)}$	阈值电压	1.5		V

订购信息(1)

器件	数量	介质	封装	出货
CSD17570Q5B	2500	13 英寸卷带	SON 5mm x 6mm 塑料封装	卷带封装
CSD17570Q5BT	250	7 英寸卷带		

(1) 要了解所有可用封装，请参阅数据表末尾的可订购产品附录。

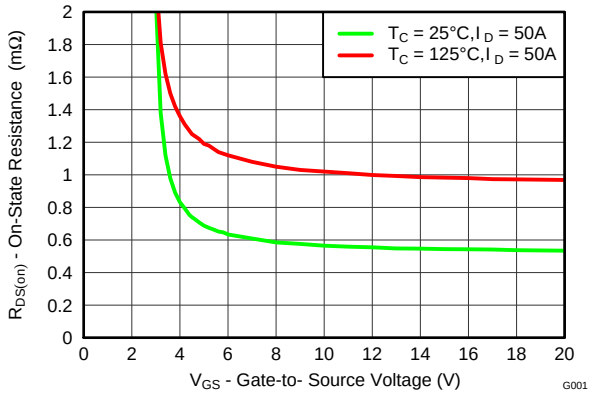
绝对最大额定值

T_A = 25°C		值	单位
V_{DS}	漏源电压	30	V
V_{GS}	栅源电压	±20	V
I_D	持续漏极电流（受封装限制）	100	A
	持续漏极电流（受芯片限制），T_C = 25°C 时测得	407	
	持续漏极电流，T_A = 25°C 时测得(1)	53	
I_{DM}	脉冲漏极电流，T_A = 25°C 时测得(2)	400	A
P_D	功率耗散(1)	3.2	W
T_J, T_{stg}	运行结温和储存温度范围	-55 至 150	°C
E_{AS}	雪崩能量，单脉冲 I_D = 90A，L = 0.1mH，R_G = 25Ω	450	mJ

(1) $R_{\theta JA}$ = 40°C/W，这是在厚度为 0.06 英寸的环氧板 (FR4) 印刷电路板 (PCB) 上的 1 英寸^2 2 盎司的铜焊盘上测得的典型值。

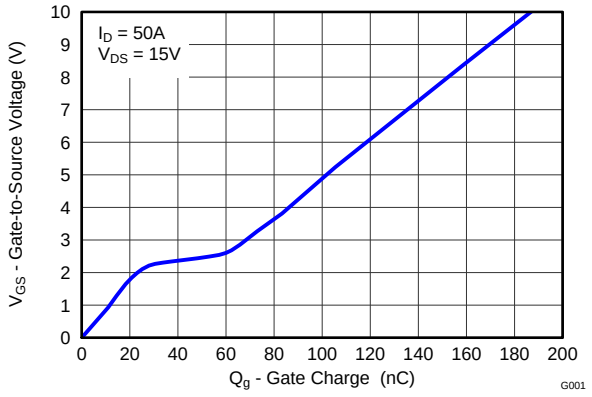
(2) 脉冲持续时间 ≤ 100μs，占空比 ≤ 2%

$R_{DS(on)}$ 与 V_{GS} 对比



G001

栅极电荷



G001

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4 修订历史记录

Changes from Revision C (January 2015) to Revision D **Page**

- 已添加 *"接收文档更新通知"*和*"社区资源"*部分添加到了*"器件和文档支持"*。 ... 7
- 已更改 将*建议 PCB 布局* 部分方框图中 ... 9

Changes from Revision B (August 2014) to Revision C **Page**

- 已将脉冲漏极电流更正为 400A。 ... 1

Changes from Revision A (May 2014) to Revision B **Page**

- Updated Figure 1 to state Max $R_{\theta JC}$ = 0.8ºC/W. ... 4
- Updated the SOA in Figure 10. ... 6

Changes from Original (February 2014) to Revision A **Page**

- 更新了机械制图。 ... 8

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5 Specifications

5.1 Electrical Characteristics

(T_A = 25°C unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
STATIC CHARACTERISTICS						
BV_{DSS}	Drain-to-Source Voltage	V_{GS} = 0 V, I_D = 250 μA	30			V
I_{DSS}	Drain-to-Source Leakage Current	V_{GS} = 0 V, V_{DS} = 24 V			1	μA
I_{GSS}	Gate-to-Source Leakage Current	V_{DS} = 0 V, V_{GS} = 20 V			100	nA
$V_{GS(th)}$	Gate-to-Source Threshold Voltage	V_{DS} = V_{GS}, I_D = 250 μA	1.1	1.5	1.9	V
$R_{DS(on)}$	Drain-to-Source On-Resistance	V_{GS} = 4.5 V, I_D = 50 A		0.74	0.92	mΩ
		V_{GS} = 10 V, I_D = 50 A		0.56	0.69	mΩ
g_{fs}	Transconductance	V_{DS} = 15 V, I_D = 50 A		271		S
DYNAMIC CHARACTERISTICS						
C_{iss}	Input Capacitance	V_{GS} = 0 V, V_{DS} = 15 V, f = 1 MHz		10400	13600	pF
C_{oss}	Output Capacitance			1450	1890	pF
C_{rss}	Reverse Transfer Capacitance			877	1140	pF
R_G	Series Gate Resistance			1.8	3.6	Ω
Q_g	Gate Charge Total (4.5 V)	V_{DS} = 15 V, I_D = 50 A		93	121	nC
Q_{gd}	Gate Charge Gate-to-Drain			34		nC
Q_{gs}	Gate Charge Gate-to-Source			27		nC
$Q_{g(th)}$	Gate Charge at V_{th}			17		nC
Q_{oss}	Output Charge	V_{DS} = 15 V, V_{GS} = 0 V		40		nC
$t_{d(on)}$	Turn On Delay Time	V_{DS} = 15 V, V_{GS} = 10 V, I_{DS} = 50 A, R_G = 0 Ω		5		ns
t_r	Rise Time			36		ns
$t_{d(off)}$	Turn Off Delay Time			144		ns
t_f	Fall Time			74		ns
DIODE CHARACTERISTICS						
V_{SD}	Diode Forward Voltage	I_{SD} = 50 A, V_{GS} = 0 V		0.8	1	V
Q_{rr}	Reverse Recovery Charge	V_{DS}= 15 V, I_F = 50 A, di/dt = 300 A/μs		34		nC
t_{rr}	Reverse Recovery Time			51		ns

5.2 Thermal Information

(T_A = 25°C unless otherwise stated)

THERMAL METRIC		MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction-to-Case Thermal Resistance(1)			0.8	°C/W
$R_{\theta JA}$	Junction-to-Ambient Thermal Resistance(1)(2)			50	

(1) $R_{\theta JC}$ is determined with the device mounted on a 1 inch^2 (6.45 cm^2), 2 oz. (0.071 mm thick) Cu pad on a 1.5 inches × 1.5 inches (3.81 cm × 3.81 cm), 0.06 inch (1.52 mm) thick FR4 PCB. $R_{\theta JC}$ is specified by design, whereas $R_{\theta JA}$ is determined by the user's board design.
(2) Device mounted on FR4 material with 1 inch^2 (6.45 cm^2), 2 oz. (0.071 mm thick) Cu.

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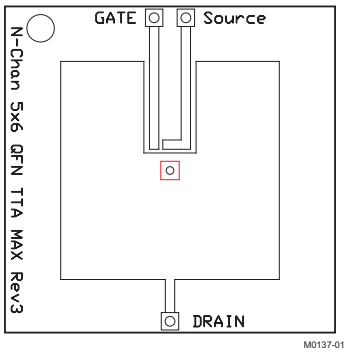
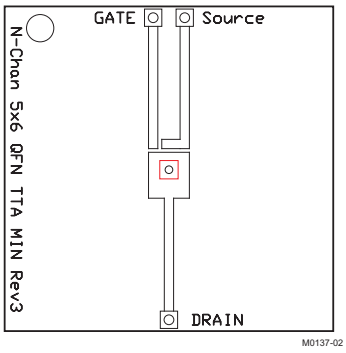


Max $R_{\theta JA}$ = 50°C/W when mounted on 1 inch^2 (6.45 cm^2) of 2 oz. (0.071 mm thick) Cu.



Max $R_{\theta JA}$ = 125°C/W when mounted on a minimum pad area of 2 oz. (0.071 mm thick) Cu.

5.3 Typical MOSFET Characteristics

(T_A = 25°C unless otherwise stated)

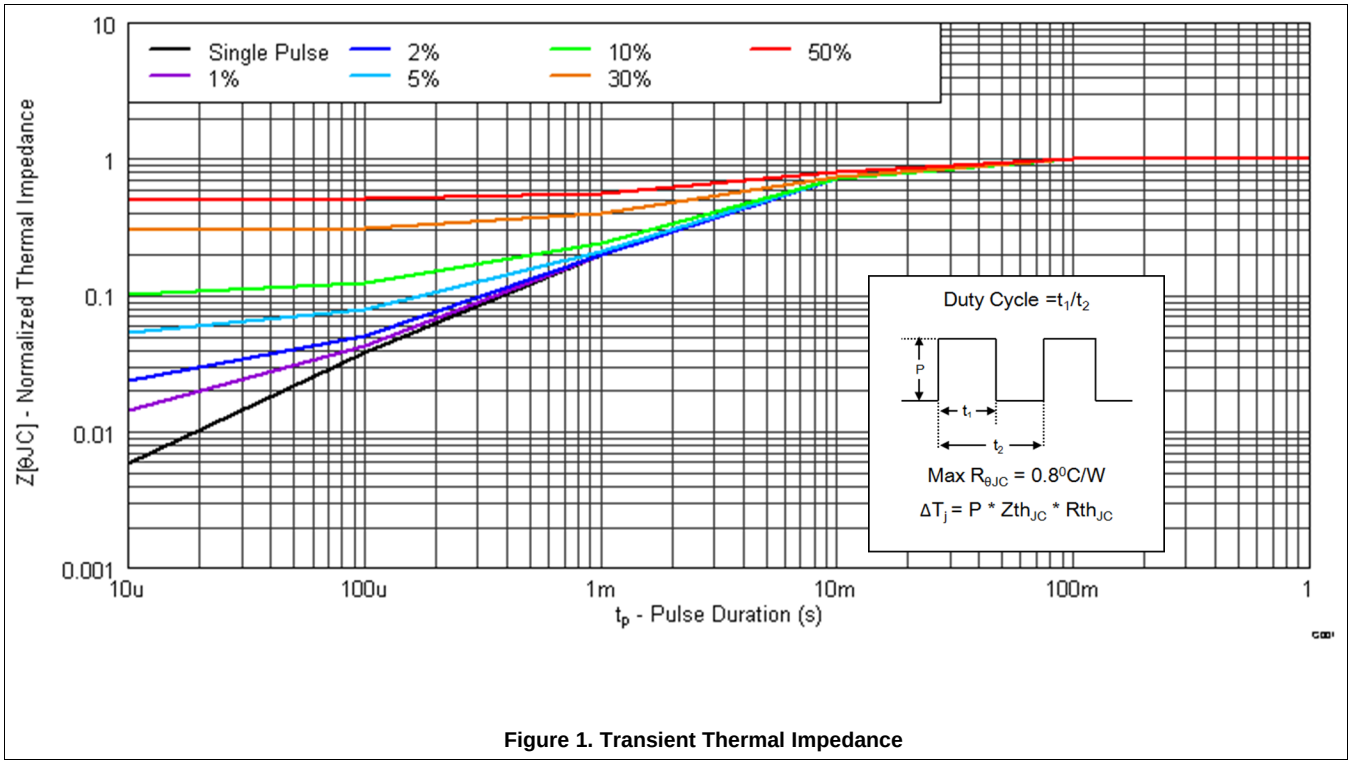


Figure 1. Transient Thermal Impedance

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Typical MOSFET Characteristics (continued)

(T_A = 25°C unless otherwise stated)

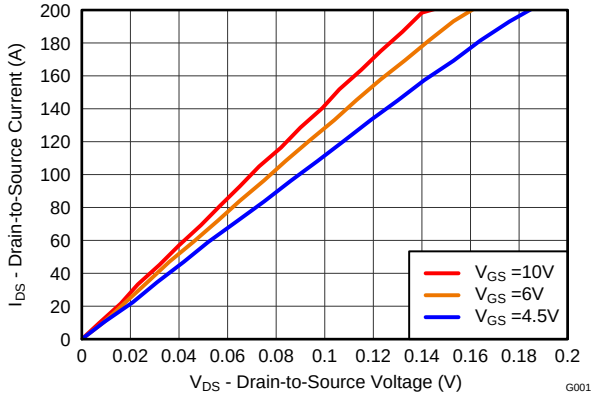

Figure 2. Saturation Characteristics

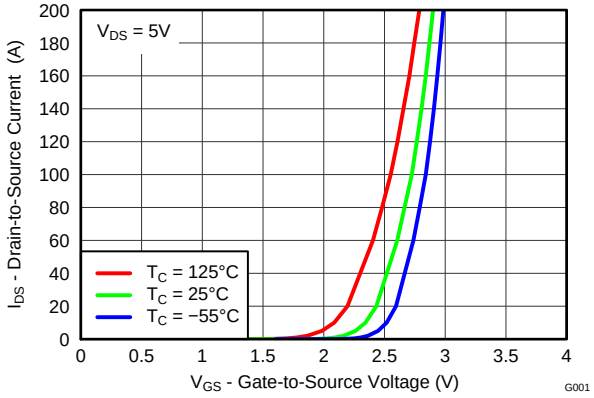

Figure 3. Transfer Characteristics

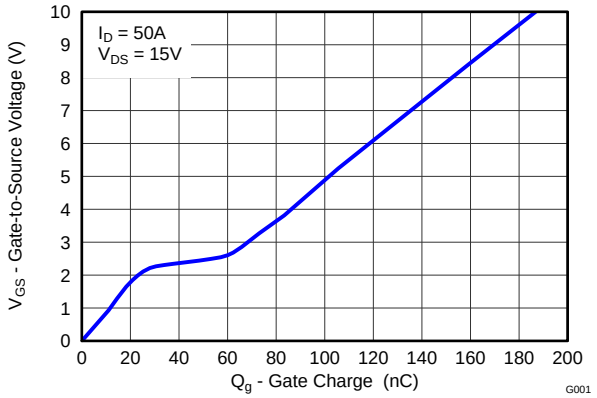

Figure 4. Gate Charge

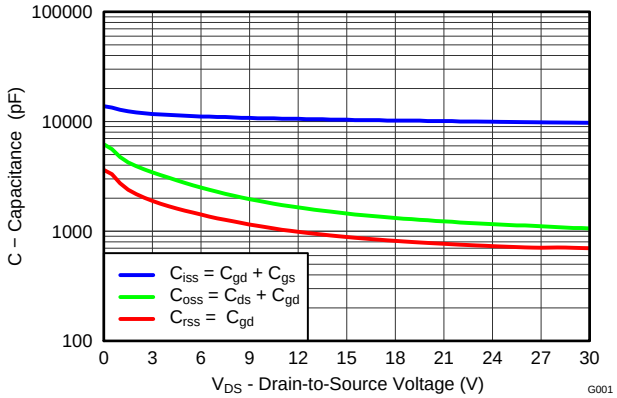

Figure 5. Capacitance

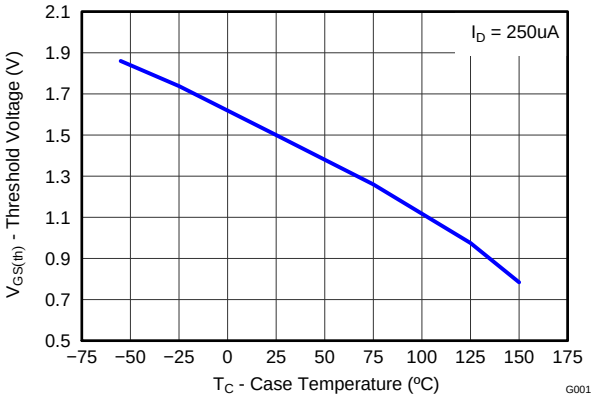

Figure 6. Threshold Voltage vs Temperature

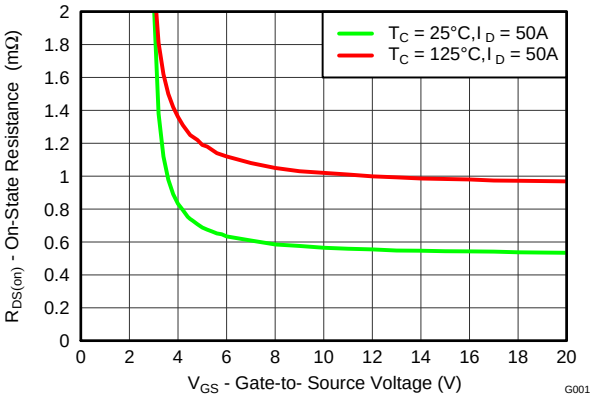

Figure 7. On-State Resistance vs Gate-to-Source Voltage

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Typical MOSFET Characteristics (continued)

(T_A = 25°C unless otherwise stated)

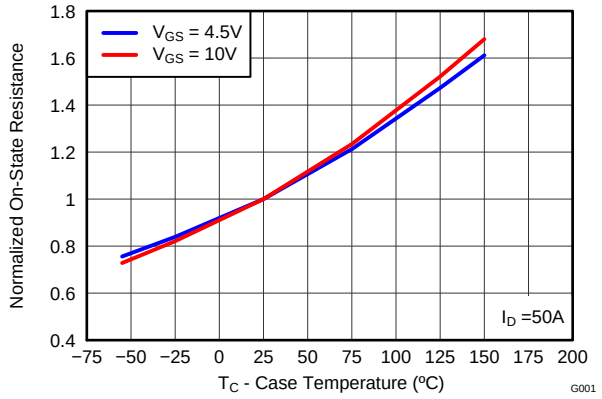

Figure 8. Normalized On-State Resistance vs Temperature

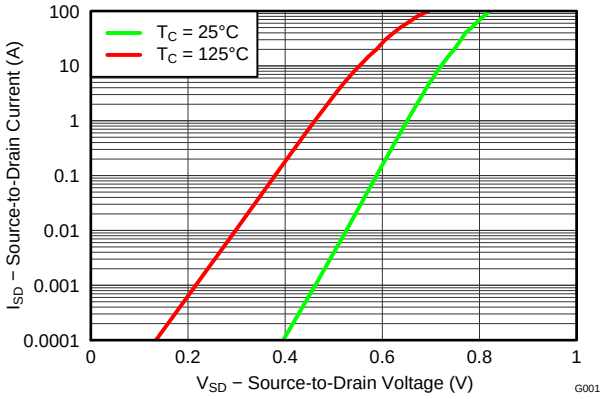

Figure 9. Typical Diode Forward Voltage

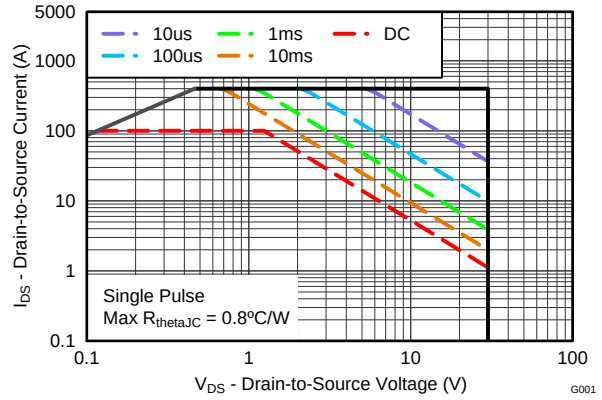

Figure 10. Maximum Safe Operating Area

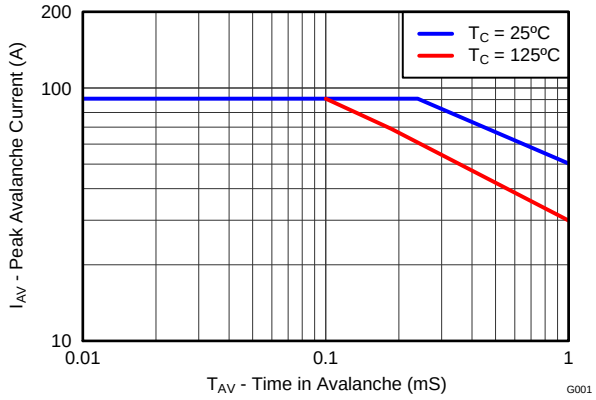

Figure 11. Single Pulse Unclamped Inductive Switching

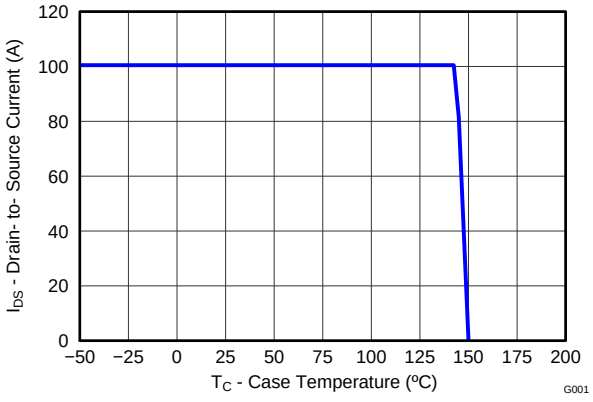

Figure 12. Maximum Drain Current vs Temperature

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6 器件和文档支持

6.1 接收文档更新通知

要接收文档更新通知，请导航至 ti.com 上的器件产品文件夹。请单击右上角的*通知我*进行注册，即可收到任意产品信息更改每周摘要。有关更改的详细信息，请查看任意已修订文档中包含的修订历史记录。

6.2 社区资源

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community ***TI's Engineer-to-Engineer (E2E) Community.*** Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support ***TI's Design Support*** Quickly find helpful E2E forums along with design support tools and contact information for technical support.

6.3 商标

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6.4 静电放电警告

这些装置包含有限的内置 ESD 保护。 存储或装卸时，应将导线一起截短或将装置放置于导电泡棉中，以防止 MOS 门极遭受静电损伤。

6.5 Glossary

SLYZ022 — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

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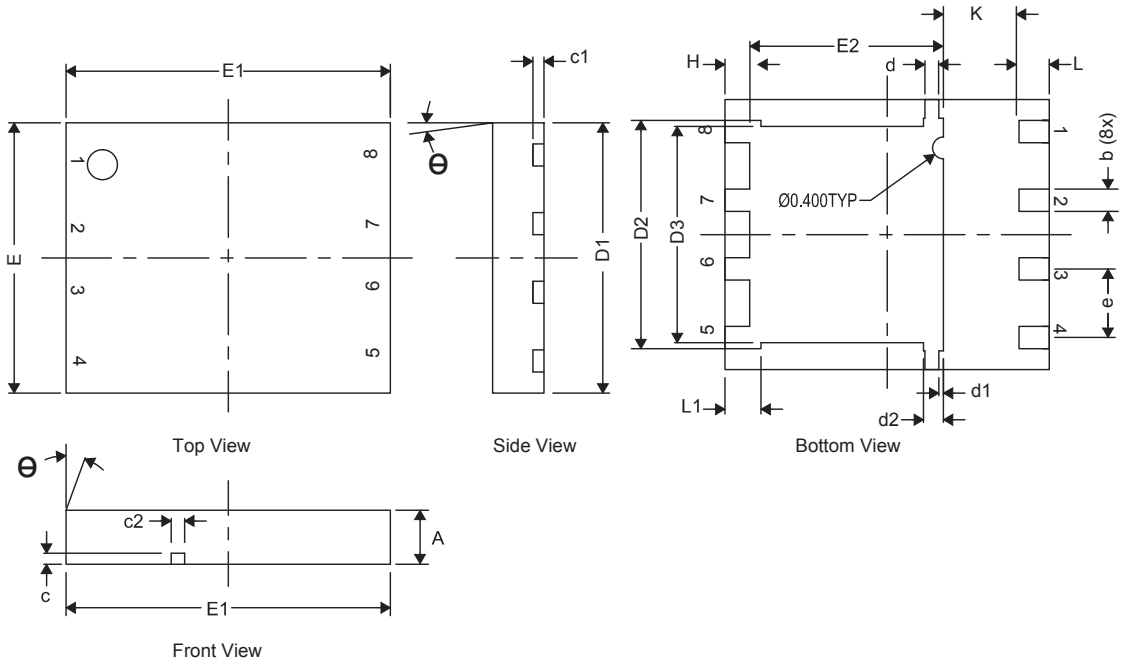
7 机械、封装和可订购信息

以下页面包括机械、封装和可订购信息。这些信息是指定器件的最新可用数据。这些数据发生变化时，我们可能不会另行通知或修订此文档。如欲获取此产品说明书的浏览器版本，请参见左侧的导航栏。

7.1 Q5B 封装尺寸



DIM	毫米		
	最小值	标称值	最大值
A	0.80	1.00	1.05
b	0.36	0.41	0.46
c	0.15	0.20	0.25
c1	0.15	0.20	0.25
c2	0.20	0.25	0.30
D1	4.90	5.00	5.10
D2	4.12	4.22	4.32
D3	3.90	4.00	4.10
d	0.20	0.25	0.30
d1	0.085 典型值		
d2	0.319	0.369	0.419
E	4.90	5.00	5.10
E1	5.90	6.00	6.10
E2	3.48	3.58	3.68
e	1.27 典型值		
H	0.36	0.46	0.56
L	0.46	0.56	0.66
L1	0.57	0.67	0.77
θ	0°	-	-
K	1.40 典型值		

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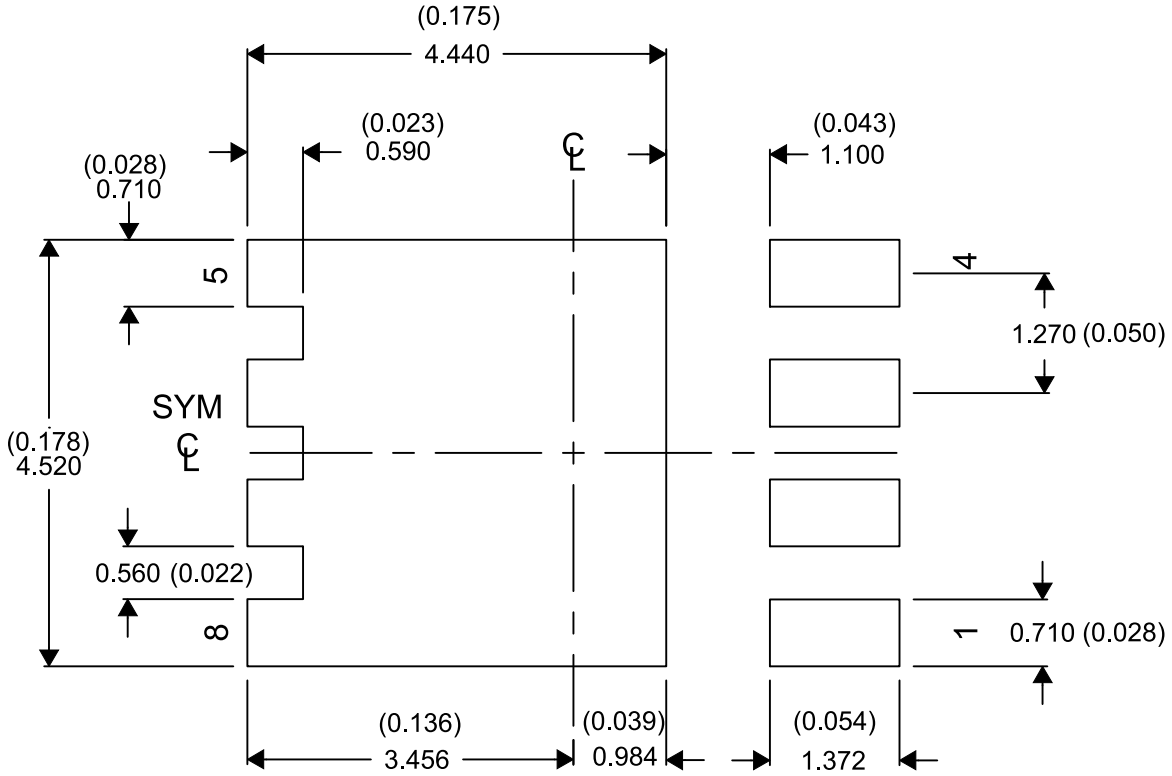
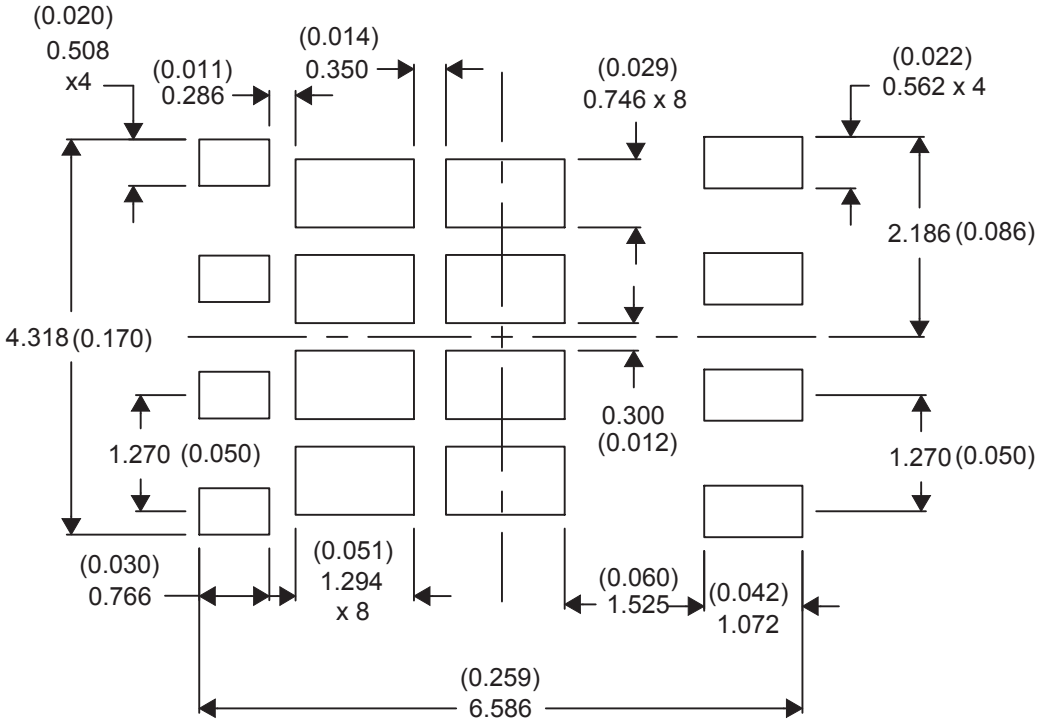
7.2 建议 PCB 布局

，焊盘 3 和 4 之间的尺寸从 0.028 英寸更改为了 0.050 英寸

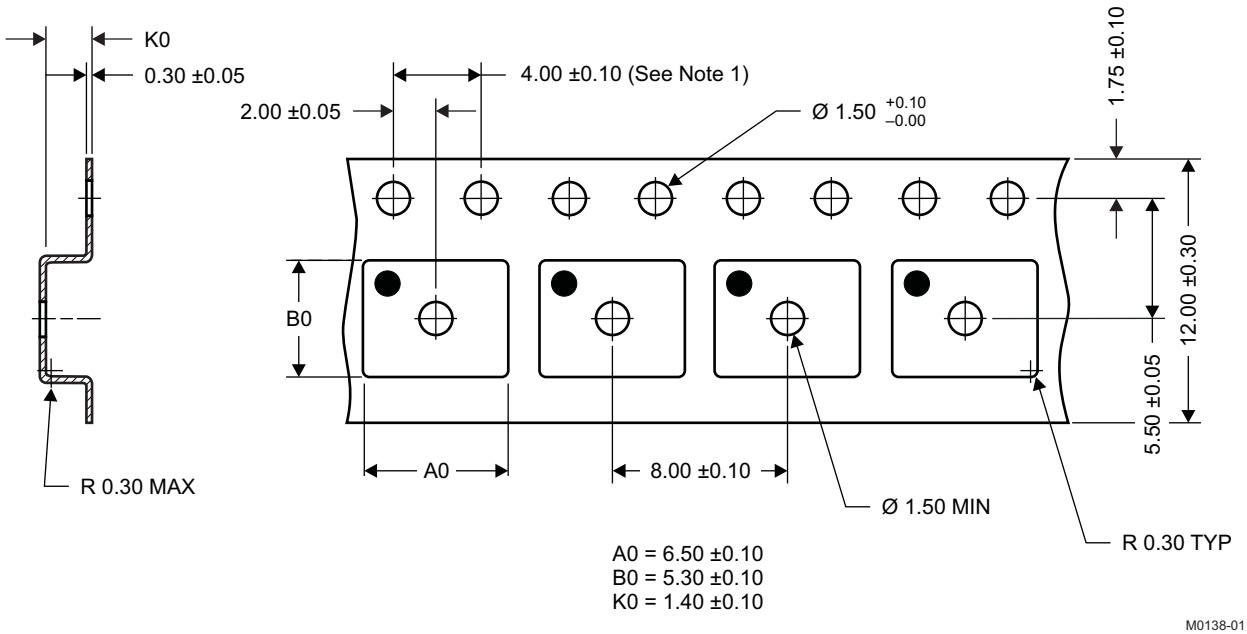


要获得与印刷电路板 (PCB) 设计相关的建议电路布局布线，请参见《应用说明》SLPA005 - *通过 PCB 布局布线技巧来减少振铃*。

7.3 建议模板布局



7.4 Q5B 卷带信息



注释：

1. 10 个链齿孔的累积容差为 ±0.2
2. 每 100mm 长度的翘曲不能超过 1mm，在 250mm 长度上不累积
3. 材料：黑色抗静电聚苯乙烯
4. 全部尺寸单位为 mm（除非另外注明）。
5. 高于孔眼底部 0.3mm 的平面上测量得到 A0 和 B0 值.

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PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package | Pins	Package qty | Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
CSD17570Q5B	Active	Production	VSON-CLIP (DNK) | 8	2500 | LARGE T&R	ROHS Exempt	NIPDAU | SN	Level-1-260C-UNLIM	-55 to 150	CSD17570
CSD17570Q5B.B	Active	Production	VSON-CLIP (DNK) | 8	2500 | LARGE T&R	ROHS Exempt	NIPDAU	Level-1-260C-UNLIM	-55 to 150	CSD17570
CSD17570Q5BG4	Active	Production	VSON-CLIP (DNK) | 8	2500 | LARGE T&R	ROHS Exempt	NIPDAU	Level-1-260C-UNLIM	-55 to 150	CSD17570
CSD17570Q5BG4.B	Active	Production	VSON-CLIP (DNK) | 8	2500 | LARGE T&R	ROHS Exempt	NIPDAU	Level-1-260C-UNLIM	-55 to 150	CSD17570
CSD17570Q5BT	Active	Production	VSON-CLIP (DNK) | 8	250 | SMALL T&R	ROHS Exempt	NIPDAU | SN	Level-1-260C-UNLIM	-55 to 150	CSD17570
CSD17570Q5BT.B	Active	Production	VSON-CLIP (DNK) | 8	250 | SMALL T&R	ROHS Exempt	NIPDAU	Level-1-260C-UNLIM	-55 to 150	CSD17570

(1) **Status:** For more details on status, see our product life cycle.

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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